

Notice of References Cited

Application/Control No.

10/820,421

Applicant(s)/Patent Under
Reexamination
CHIU ET AL.

Examiner

John Juba, Jr.

Art Unit

2872

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2004/0201889 A1	10-2004	Wang et al.	359/486
	B	US-6,122,103	09-2000	Perkins et al.	359/486
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	M	US-			

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NON-PATENT DOCUMENTS

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.